

<b>Notice of References Cited</b>	Application/Control No. 09/754,441	Applicant(s)/Patent Under Reexamination YOSHIHARA ET AL.	
	Examiner Hai V. Nguyen	Art Unit 2142	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,734,119	03-1998	France et al.	84/622
*	B	US-6,360,275	03-2002	Chu et al.	709/245
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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